

**Search Notes**

Application/Control No.

10/726,510

Examiner

Duc Nguyen

Applicant(s)/Patent under  
Reexamination

SHIH ET AL.

Art Unit

2643

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR